

### > Mechanical Specification:

(1) Dimension

- Chip size:  $305 \pm 25 \mu\text{m} \times 305 \pm 25 \mu\text{m}$
- Thickness:  $110 \pm 10 \mu\text{m}$
- P bonding pad:  $90 \pm 10 \mu\text{m}$
- N bonding pad:  $90 \pm 10 \mu\text{m}$

(2) Metallization

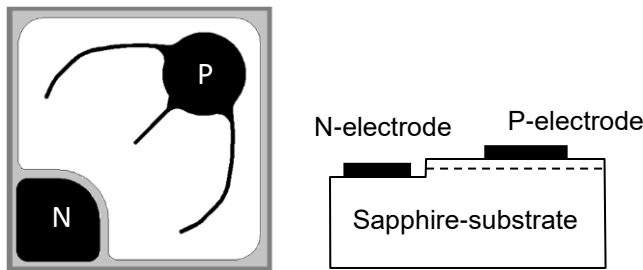
- Topside P electrode: Au alloy
- Topside N electrode: Au alloy

**Features:**

- High radiant flux
- Long operation life
- Lambertian radiation

**Applications:**

- Automotive



### > Electro-optical Characteristics at 25°C: (1)

| Parameter                          | Symbol         | Condition           | Min.      | Typ. | Max. | Unit |    |
|------------------------------------|----------------|---------------------|-----------|------|------|------|----|
| Forward Voltage                    | Vf1            | If = 10μA           | 2.0       | -    | -    | V    |    |
|                                    | Vf2            | If = 20mA           | -         | 2.9  | 3.2  | V    |    |
| Reverse Current                    | I <sub>r</sub> | V <sub>r</sub> = 5V | -         | -    | 1.0  | μA   |    |
| Dominant Wavelength <sup>(2)</sup> | λ <sub>d</sub> | If = 20mA           | 450       | -    | 470  | nm   |    |
| Spectra Half-width                 | Δλ             | If = 20mA           | -         | 25   | -    | nm   |    |
| Radiant Flux <sup>(3)(4)</sup>     | P <sub>o</sub> | A29                 | If = 20mA | 28   | -    | 29   | mW |
|                                    |                | A30                 |           | 29   | -    | 30   |    |
|                                    |                | A31                 |           | 30   | -    | 32   |    |
|                                    |                | A32                 |           | 32   | -    | 34   |    |
|                                    |                | A33                 |           | 34   | -    | 36   |    |

Note:  
 (1) ESD protection during chip handling is recommended.  
 (2) Basically, the wavelength span is 20nm; however, customers' special requirements are also welcome.  
 (3) Radiant flux is determined by using an Ag-plated TO-can header without an encapsulant.  
 (4) Radiant flux measurement allows a tolerance of ±15%.

### > Absolute Maximum Ratings:

| Parameter                                 | Symbol | Condition                   | Rating      | Unit |
|---|--------|-----------------------------|-------------|------|
| Forward DC Current                        | If     | Ta = 25°C                   | ≤ 50        | mA   |
| Reverse Voltage                           | Vr     | Ta = 25°C                   | ≤ 5         | V    |
| Junction Temperature                      | Tj     | -                           | ≤ 125       | °C   |
| ESD withstand voltage(HBM) <sup>(2)</sup> | VESD   | -                           | Up to 2     | KV   |
| Storage Temperature                       | Tstg   | Chip                        | -40 ~ +85   | °C   |
|   |        | Chip-on-tape/storage        | 5 ~ 35      | °C   |
|   |        | Chip-on-tape/transportation | -20 ~ +65   | °C   |
| Temperature during Packaging              | -      | -                           | 280(<10sec) | °C   |

Note: (1) Maximum ratings are package dependent. The above maximum ratings were determined using a Printed Circuit Board (PCB) without an encapsulant. Stresses in excess of the absolute maximum ratings such as forward current and junction temperature may cause damage to the LED.

(2) According to ANSI/ESDA/JEDEC JS-001

### > Characteristic Curves:

Fig.1 – Relative luminous Intensity vs. Forward Current

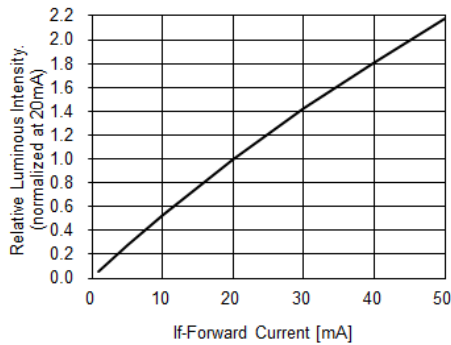


Fig.2 – Forward Current vs. Forward Voltage

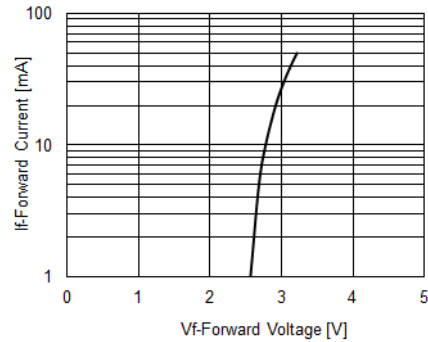


Fig.3 – Relative Intensity (@20mA) vs. Ambient Temperature

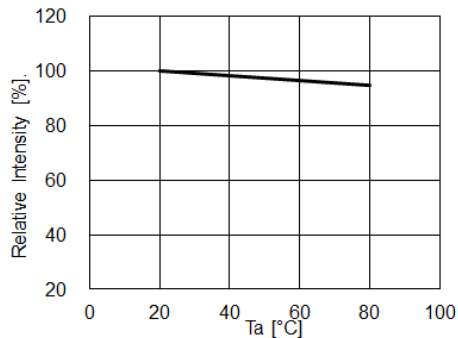


Fig.4 – Forward Voltage (@20mA) vs. Ambient Temperature

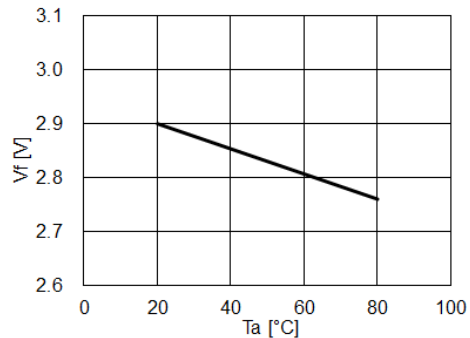


Fig.5 – Dominant Wavelength (@20mA) vs. Ambient Temperature

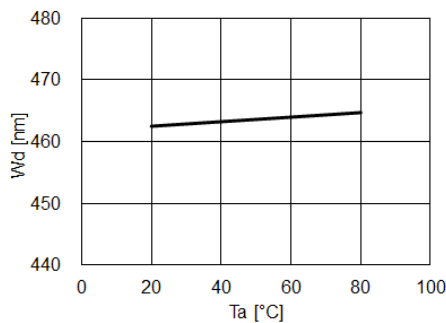
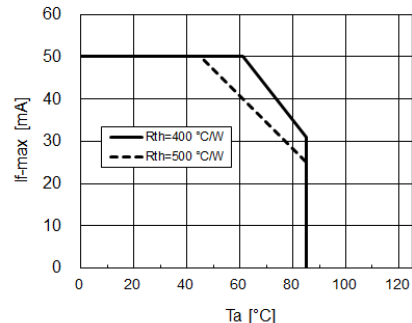


Fig.6 – Maximum Driving Forward DC Current vs. Ambient Temperature (De-rating based on Tj max. = 125°C)



**> Qualification:**

- <sup>1)</sup> EPISTAR's LED chips and epi-wafers are designed and manufactured according to the quality management system that complies to the IATF 16949:2016 requirements (IATF No: 0325277/ Certificate Registration No: 20000910 IATF16).
- <sup>2)</sup> The chip qualification test plan is based on the guidelines of AEC-Q101-REV-D, Failure Mechanism Based Stress Test Qualification for Discrete Semiconductors in Automotive Applications.

**> Revision:**

| Version | Page | Subjects        | Date of Modification |
|---------|------|-----------------|----------------------|
| A       | 3    | Initial Release | December, 2019       |